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Dk & Df ALGEBRAIC MODEL v2.04

(NOTE: only change from y2.03 is correction of Cu conductivity used in surface roughness [Hurray model] calculation)

Let's take a look...

WHAT YOU WILL SEE

Unchanged from v2.01

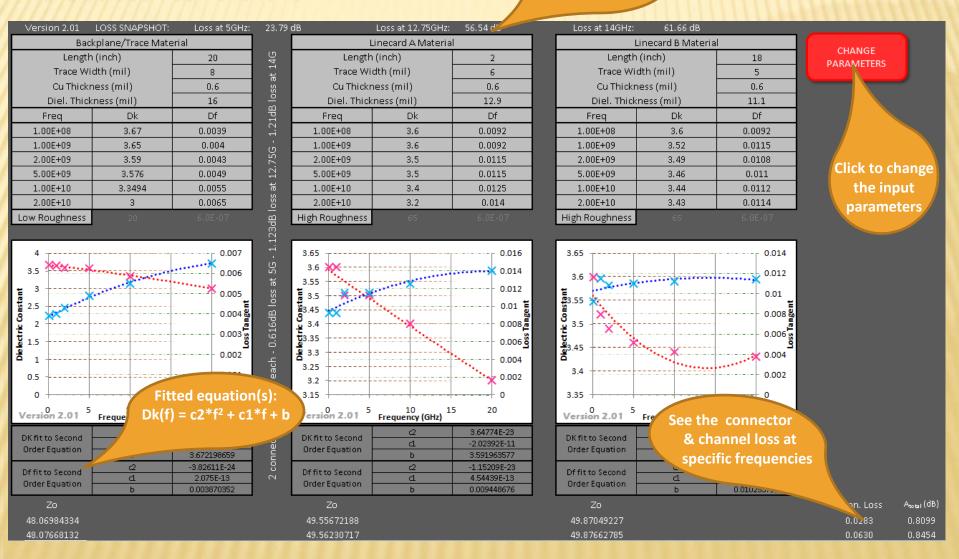
LOOK & FEEL

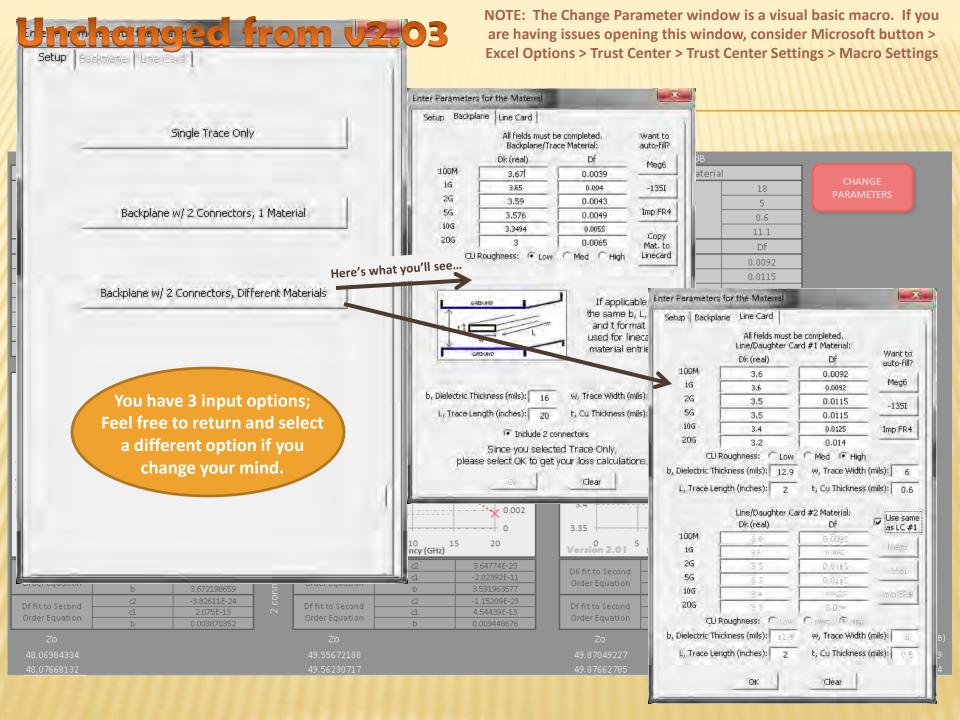
NOTE: The Change Parameter window is a visual basic macro.

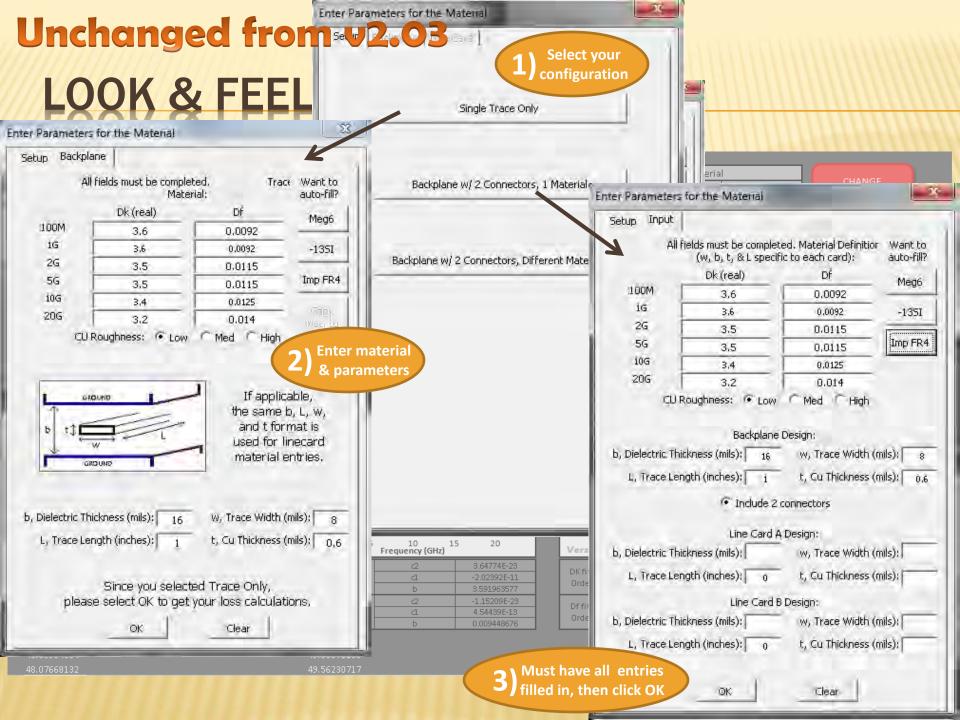
If you save the file to your computer, be sure to select the

Maco-Enabled file type.

Quick preview of select frequencies

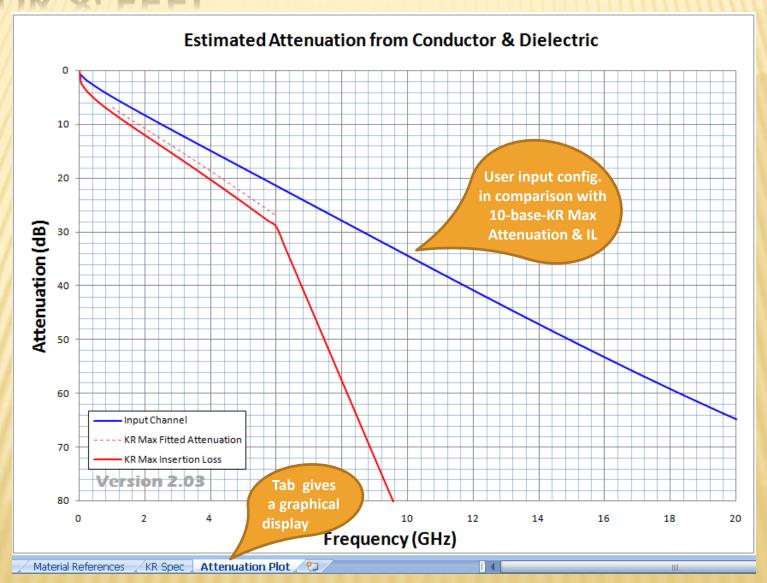






Unchanged from v2.03

LOOK & FEEL



Behind the Scenes...

EQUATIONS AND REFERENCES OF MODEL

FREQUENCY DEPENDENCE

- and Df
- × 6 input frequency points for Dk and Df
- Fit Dk and Df to second order equations
 - + Coefficients shown on sheet
 - + Graphical representation shown on sheet
- Note that frequency dependence fit is only approximated to 20G, therefore, loss approximations should only be considered to 20G
- × Z₀ is calculated with Dk (or ε_r) at a given frequency; a similar technique is used in loss calculations

DK & DF SECOND ORDER EQUATIONS

* Second order approximation is created using the LINEST function. This function essentially fits a 2nd order polynomial to the 6 frequency points given; resulting in

$$D_k = c_2 * f^2 + c_1 * f + b$$

Function as implemented in the spreadsheet:

LINEST(C8:C13,B8:B13^[1,2])

Y Values
(Dk entered points)

X Values (Freq. associated w/ entered points)

Exponents of X; Creating a second order equation.

See Excel HELP for more details on LINEST function.
Methodology verified against "add trend line" within plot.

$$Z_{0} = \frac{94.15}{\sqrt{\varepsilon_{r}} \left(\frac{\frac{w}{b}}{\frac{1-t}{b}} + \frac{c_{f}^{'}}{0.0885\varepsilon_{r}} \right)} ohms$$

$$c_{f}' = \frac{0.0885\varepsilon_{r}}{\pi} \left\{ \frac{2}{1 - \frac{t}{b}} \log_{e} \left(\frac{1}{1 - \frac{t}{b}} + 1 \right) - \left(\frac{1}{1 - \frac{t}{b}} - 1 \right) \log_{e} \left(\frac{1}{\left(1 - \frac{t}{b} \right)^{2}} - 1 \right) \right\}$$

 ε_r = relative dielectric constant (at a given frequency)

b = platespacing (mil)

w = trace width (mil)

t =trace thickness (mil)

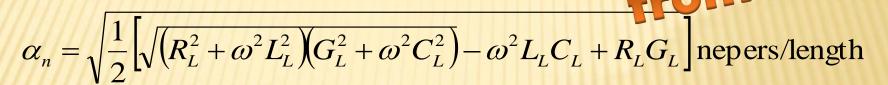




 $c_f = fringing \ capacitance \ (\mu f/cm) * assuming semi - infinite plate between two infinite ground planes, but good approximation for w/(b - t) <math>\geq 0.35$

ATTENUATION IN LOSSY LINES

* Attenuation per length^[1, EQN 9-54]:



★ Using a low-loss approximation^[1, EQN 9-55]: (surface roughness ignored)

$$\alpha_n = \frac{1}{2} \left(\frac{R_L}{Z_0} + G_L Z_0 \right)$$
 nepers/length

★ But we don't typically discuss in nepers...^[1, EQN 9-57]

$$10^{\frac{\alpha_{dB}}{20}} = e^{\alpha_n} \qquad \therefore \alpha_{dB} = 20 \log_{10} e \times \alpha_n$$

for ease of notation: $Y_{n\to dB} = 20\log_{10} e$

Unchanged CONDUCTOR LOSS (per inch) from v2.01

$$\alpha_{cond} = \left(Y_{n \to dB}\right) \times \frac{R_L}{Z_0} \begin{cases} \alpha_{cond} = \text{attenuation of amplitude due to conductor loss, in dB/length}^{[1, EQN 9-59]} \\ Y_{n \to dB} = \text{converstion from nepers to dB} \\ R_L = \text{resistance per length of conductor} \\ Z_0 = \text{characteristic impedance} \end{cases}$$

- Skin effect, ground resistance, and stripline effect are accounted for in resistance^[3, EQNs 4.3a-4.10]:
 - R of signal trace & return path (w/skin effect)

$$R_{signalCu\,skin\,effect} = rac{\sqrt{\pi\mu\rho f}}{w}$$
 $R_{groundCu\,skin\,effect} = rac{\sqrt{\pi\mu\rho f}}{6H}$

AC surface resistance for microstrip (or 1 side of a stripline trace) $R_{ac\,microstrip} = R_{signal} + R_{ground}$

Unchanged

NDUCTOR LOSS (per inch) from v2.02

Stripline approximation assumes parallel resistance of top and bottom microstrip approximations

$$R_{L} = \frac{\left[\sqrt{\pi\mu\rho f} * \left(\frac{1}{w} + \frac{1}{6H}\right)\right]^{2}}{2*\left[\sqrt{\pi\mu\rho f} * \left(\frac{1}{w} + \frac{1}{6H}\right)\right]}$$

$$R_L = \frac{\left[\sqrt{\pi\mu\rho f} * \left(\frac{1}{w} + \frac{1}{6H}\right)\right]^2}{2*\left[\sqrt{\pi\mu\rho f} * \left(\frac{1}{w} + \frac{1}{6H}\right)\right]} \begin{cases} R_L = \text{strip line surface resistance } (\Omega/\text{inch}) \\ w = \text{ width of trace (inch)} \\ H = \text{ height dielectric from ground to signal (inch)} \end{cases} \\ \mu = \text{ permeability of } \text{Cu} \approx 4\pi \times 10^{-7} \times 0.999994} \quad \frac{\text{H}}{\text{m}} \\ \rho = \text{ resistivity of } \text{Cu} = \frac{1}{\sigma} = \frac{1}{5.96 \times 10^7} \quad \Omega \text{ m} \\ f = \text{ frequency (hertz)} \end{cases}$$

Conductor loss per inch as entered in the model:

$$\alpha_{cond} = \frac{1}{2} \times (20\log_{10} e) \times \left(\frac{\sqrt{\pi\mu\rho f} * \left(\frac{1}{w} + \frac{1}{6H}\right)}{2}\right) \times \frac{1}{Z_0}$$

$$\alpha_{diel} = (Y_{n \to dB}) \times G_L Z_0 \begin{cases} Y_{n \to dB} = \text{converstion from nepers to dB} \\ G_L = \text{shunt conductance per length from dielectric} \end{cases}$$

 $\alpha_{\rm cond}$ = attenuation of amplitude due to dielectric loss, in dB/length [1,EQN 9-60]

Unchanged from v1.01

 Z_0 = characteristic impedance

As developed by Bogatin...

$$G_{L} = \omega \tan(\delta) C_{L}$$

$$Z_{0} = \frac{\sqrt{\varepsilon_{r}}}{cC_{L}}$$

 G_L equation [1, EQN 9-19, EQN 9-60]

 Z_0 equation^[1,EQN 9-67] is used to cancel the capacitance value, the Z₀ value for a given frequency is NOT used c = speed of light m/s :: converstion m \rightarrow in. is needed

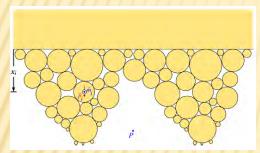
Dielectric loss per inch as entered in the model:

$$\alpha_{diel} = \frac{1}{2} \times (20 \log_{10} e) \times (2\pi f \times D_f) \times \frac{\sqrt{\varepsilon_r}}{299792458 * 39.37}$$

affecting δ which, in turn, impacted $k_{snowball}$, and thus total loss.

SURFACE ROUGHNESS (multiplier)

* Through the snowball method (Huray Model^[4, CHAP 6]), surface roughness is approximated as a collection of



smaller spheres. *Note image shows non-uniform "snowballs"... model approximates using uniform spheres.

$$\star$$
 Applied to trace: $\alpha_{total} = \alpha_{diel} + k_{snowbal} \alpha_{cond(smooth)}$

× Surface roughness multiplier as entered in the model:

$$k_{snowball} \approx 1 + \frac{3}{2} \sum_{i=1}^{j} \frac{\left(\frac{N_i 4\pi a_i^2}{A_{flat}}\right)}{\left(1 + \frac{\delta}{a_i} + \frac{\delta^2}{2a_i^2}\right)}$$

$$a_i$$
 = radius of spheres (m)
 N_i = number of snowballs of size a_i per A_{flat}

 A_{flat} = total area containing stacked snowballs

$$\delta = \text{skin depth (m)} \quad \dots \text{ recall : } \delta = \frac{1}{\sqrt{\pi \mu o f}}$$

CONNECTOR LOSS & CHANNEL LOSS

- Attempting to base on 25G technology connectors
- Used connector models from multiple vendors to draw this max* connector loss... used in model:

$$\left| IL_{conn} = 9*10^{-6} * \sqrt{f} - 1.2*10^{-12} * f + 1.6*10^{-21} f^{2} \right|$$

- * Max loss when ignoring majority of ILD. Idea was to create equation that production connectors can beat. Note that this creates additional error in comparing model to measured, however, model should error in pessimistic direction. Connector implementation likely to be changed in future versions.
- Equation gives loss of: 0.6164dB @5G; 1.133dB @12.89G; 1.21dB @14G
- **VERALL CHANNEL LOSS EQUATION:** (simple enough, right?)

$$A_{total} = a_{LCA_total} * L_{LCA} + IL_{conn} + a_{BP_total} * L_{BP} + IL_{conn} + L_{LCB_total} * L_{LCB}$$

REFERENCES



- [1] E. Bogatin. Signal Integrity Simplified. Pearson Education, Inc., 2004. ISBN 0-13-066946-6.
- [2] S. B. Cohn. "Problems in Strop Transmission Lines." *IRE Trans. Microwave Theory and Techniques*, Vol. MTT-3, March, 1955, pp 119-126.
- [3] S. H. Hall, G.W.Hall, J. A. McCall. High-Speed Digital System Design: A Handbook of Interconnect Theory and Design Practices. John Wiley & Sons, Inc., 2000. ISBN-10 0471360902.
- [4] P. G. Huray. The Foundations of Signal Integrity. John Wiley & Sons, Inc., 2010. ISBN-978-0-470-34360-9

TRACKING THE CHANGES

Version	Change
1.01	9/26/2011 – Initial release – second order Dk & Df approximation, track user input channel along with Meg-6 & Improved FR-4 for given length/width/thickness, 3 materials compared to KR limit line.
2.01	12/15/2011 – surface resistance updated to include return path resistance and stripline approximation, Huray model for surface roughness added, "worst-case" connector added, partitioning option added (backplane w/2 daughter cards), KR limit comparison made to attenuation max (instead of IL)
2.02 (a)	1/9/2012 – correction of error found in final multiplication/addition (A _{total})
2.03	2/1/2012 – correction of error found in surface roughness multiplier (K _{snowball}) for line cards (matched equation given in the explanation slides), GUI clarified for "Backplane w/ 2 connectors, same material".